

Application/Control No.	Applicant(s)/Patent under Reexamination
10/761,394	BURTON ET AL.
Examiner	Art Unit
Afsar M. Oureshi	2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	360,389 392,412	10/24/2007	AQ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	ce search uded	10/24/2007	AQ		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Class search, EAST, WEST, IEEE	10/24/2007	AQ		
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